	Application Number		10820525
	Filing Date		2004-04-07
INFORMATION DISCLOSURE	First Named Inventor	Wu et	al.
STATEMENT BY APPLICANT (Not for submission under 37 CFR 1.99)	Art Unit		2823
( Not for submission under 37 CFK 1.33)	Examiner Name	Maldo	onado, J.
	Attorney Docket Numb	er	NOVLP091/NVLS-2889

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/J.M./	1	6383955		2002-05-07	Matsuki et al.	column 3, line 48 - column 12, line 59
/J.M./	2	6662631		2003-12-16	Baklanov, et al.	column 3, line 35 - column 5, line 9
/J.M./	3	7098149		2006-08-29	Lukas, et al.	Figs.la-lc and column 8, line 51 - column 10, line 10.
/J.M./	4	6572925		2003-06-03	Zubkov, et al.	column 6, line 53 - column 9, line 45; column 10, lines 12-27
/J.M./	5	6566278		2003-05-20	Harvey, et al.	Fig. 6 and column 11, line 40 - column 12, line 62
/J.M./	6	6413583		2002-07-02	Moghadam, et al.	Figs.7A-7E and column 4, line 38 - column 15, line 48
/J.M./	7	6407013		2002-06-18	Li, et al.	Figs.1-5 and column 5, line 35 - column 10, line 517
/J.M./	8	6365528		2002-04-02	Sukharev, et al.	column 3, line 11 - column 5, line 63
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/J.M./	1	WO 03/052794	wo			2003-06-26	AVANZINO et al.		Figs.3-7 and page 4, line 25-6, line 9	
/J.M./	2	WO 03/005429	wo			2003-01-16	RHEE et al.		page 4, line 14 - page 6, line 24	
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/J.M./	1	U.S. Office Action mailed NVLS-2919].	d January 24	4, 2007	, from U	J.S Application	No. 10/789,103 [Atty	Dkt No	. NOVLP094/	
/J.M./	2	U.S. Office Action mailed	d June 21, 2	:007, fre	om U.S	Application No	. 10/789,103 [Atty Dk	t No. N	OVLP094/NVLS-2919].	

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/J.M./	3	U.S. Notice of Allowance and Fee Due mailed December 19, 2006, from U.S. Application No. 10/800,409. [NOVLP098/NVLS-2907]	Z
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/J.M./	5	Niu et al., "Methods for Improving the Cracking Resistance of Low-K Dielectric Materials," Novellus Systems, Inc., Appl. No. 11/376,510, filed March 14,2006, pages 1-28. [NOVLP099D1/NVLS-2896D1]	Z
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/J.M./	8	Allowed Claims from U.S. Application No. 10/927,777. [NOVLP106/NVLS-2930]	Z
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Continuation of Substance of Interview including description of the general nature of what was agreed to if an agreement was reached, or any other comments: On a telephone interview with the attorney of record, Denise Bergin, the examiner pointed out that claims 32 and 33 were improperly amended under CFR §1.121. The examiner suggested the attorney of record, under the examiner's supervisor's recommendation, to cancel claims 32 and 33, and add newly claims 34 and 35.

The attorney of record, Denise Bergin authorized the cancellation of claims.

The application has been amended as follows: In the claims:

Cancel claims 32 and 33.

#### Add new claims:

34. (New) The method of claim 1 wherein the deposited carbon doped oxide layer is an interlayer dielectric (ILD) in a partially or fully fabricated semiconductor device.

35. (New) The method of claim 1 the wherein the deposited carbon doped oxide layer has a carbon-carbon triple bond to silicon oxide bond ratio of about 0.05% to 20% based on FTIR peak area.